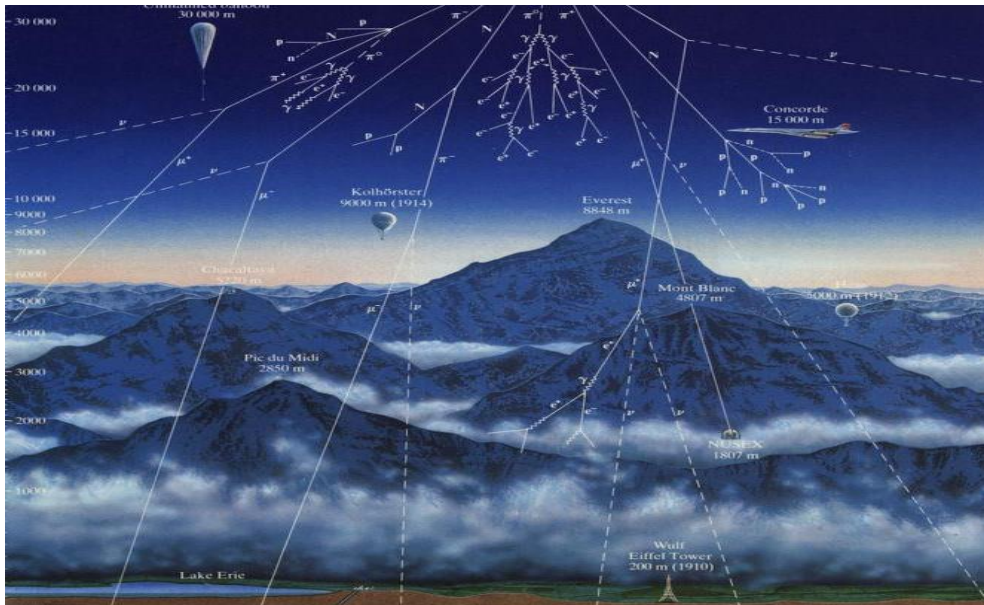


Radiation Hardening: background, definition and solutions in Smart Power Technologies

Speaker: **Andrea M. Veggetti (STMicroelectronics)**



Abstract: Soft errors caused by wandering particles hitting electronic devices are a major reliability concern in all critical applications. On Earth, the major sources of ionizing radiation responsible for these effects are atmospheric neutrons, and alpha-emitting contaminants inside chip and package materials. In this presentation it will be presented the impact on semiconductor devices and the techniques used to mitigate/prevent their effects.